

October 1987 Revised January 2004

### **CD4027BC**

## **Dual J-K Master/Slave Flip-Flop with Set and Reset**

### **General Description**

The CD4027BC dual J-K flip-flops are monolithic complementary MOS (CMOS) integrated circuits constructed with N- and P-channel enhancement mode transistors. Each flip-flop has independent J, K, set, reset, and clock inputs and buffered Q and  $\overline{\rm Q}$  outputs. These flip-flops are edge sensitive to the clock input and change state on the positive-going transition of the clock pulses. Set or reset is independent of the clock and is accomplished by a high level on the respective input.

All inputs are protected against damage due to static discharge by diode clamps to  $V_{DD}$  and  $V_{SS}$ .

### **Features**

■ Wide supply voltage range: 3.0V to 15V

■ High noise immunity: 0.45 V<sub>DD</sub> (typ.)

■ Low power TTL compatibility: Fan out of 2 driving 74L

or 1 driving 74LS

■ Low power: 50 nW (typ.)

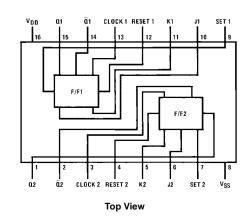
■ Medium speed operation: 12 MHz (typ.) with 10V

supply

### **Ordering Code:**

Order Number	Package Number	Package Description
CD4027BCM	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
CD4027BCN	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

### **Connection Diagram**



### **Truth Table**

Inputs t <sub>n-1</sub> (Note 1)						Outputs t <sub>n</sub> (Note 2)		
CL (Note 3)	J	K	S	R	Q	Q	Q	
	I	Χ	0	0	0	ı	0	
~	Χ	0	0	0	- 1	I	0	
~	0	Χ	0	0	0	0	1	
~	Χ	I	0	0	I	0	1	
~	Χ	Χ	0	0	Χ		(No Change)	
Х	Χ	Χ	I	0	Χ	I	0	
Х	Χ	Χ	0	I	Χ	0	1	
Х	Χ	Χ	I	I	Χ	I	1	

I = HIGH Level

O = LOW Level

X = Don't Care

Note 1:  $t_{n-1}$  refers to the time interval prior to the positive clock pulse transition

Note 2:  $t_{\rm n}$  refers to the time intervals after the positive clock pulse transition

Note 3: Level Change

# CD4027BC Logic Diagram SLAVE

### **Absolute Maximum Ratings**(Note 4)

(Note 5)

 $\begin{array}{ll} \text{DC Supply Voltage (V}_{\text{DD}}) & -0.5 \text{ V}_{\text{DC}} \text{ to +18 V}_{\text{DC}} \\ \text{Input Voltage (V}_{\text{IN}}) & -0.5 \text{V to V}_{\text{DD}} +0.5 \text{ V}_{\text{DC}} \\ \text{Storage Temperature Range (T}_{\text{S}}) & -65^{\circ}\text{C to +150}^{\circ}\text{C} \end{array}$ 

Power Dissipation (P<sub>D</sub>)

 Dual-In-Line
 700 mW

 Small Outline
 500 mW

Lead Temperature (T<sub>L</sub>)

(Soldering, 10 seconds) 260°C

# Recommended Operating Conditions (Note 5)

DC Supply Voltage ( $V_{DD}$ ) 3V to 15  $V_{DC}$ Input Voltage ( $V_{IN}$ ) 0V to  $V_{DD}$   $V_{DC}$ Operating Temperature Range ( $T_A$ ) -55°C to +125°C

Note 4: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the devices should be operated at these limits. The table of "Recommended Operating Conditions" and "Electrical Characteristics" provides conditions for actual device operation.

Note 5:  $V_{SS} = 0V$  unless otherwise specified.

### DC Electrical Characteristics (Note 6)

Symbol	Parameter	Conditions	-55	–55°C		+25°C			+125°C	
	rarameter	Conditions	Min	Max	Min	Тур	Max	Min	Max	Units
I <sub>DD</sub>	Quiescent Device Current	$V_{DD} = 5V$ , $V_{IN} = V_{DD}$ or $V_{SS}$		1			1		30	
		$V_{DD} = 10V$ , $V_{IN} = V_{DD}$ or $V_{SS}$		2			2		60	μΑ
		$V_{DD} = 15V$ , $V_{IN} = V_{DD}$ or $V_{SS}$		4			4		120	
V <sub>OL</sub>	LOW Level	I <sub>O</sub>   < 1 μA								
	Output Voltage	$V_{DD} = 5V$		0.05		0	0.05		0.05	
		$V_{DD} = 10V$		0.05		0	0.05		0.05	V
		V <sub>DD</sub> = 15V		0.05		0	0.05		0.05	
V <sub>OH</sub>	HIGH Level	I <sub>O</sub>   < 1 μA								
	Output Voltage	$V_{DD} = 5V$	4.95		4.95	5		4.95		
		$V_{DD} = 10V$	9.95		9.95	10		9.95		V
		V <sub>DD</sub> = 15V	14.95		14.95	15		14.95		
V <sub>IL</sub>	LOW Level	$V_{DD} = 5V, V_{O} = 0.5V \text{ or } 4.5V$		1.5			1.5		1.5	
	Input Voltage	$V_{DD} = 10V, V_{O} = 1V \text{ or } 9V$		3.0			3.0		3.0	V
		$V_{DD} = 15V, V_{O} = 1.5V \text{ or } 13.5V$		4.0			4.0		4.0	
V <sub>IH</sub>	HIGH Level	$V_{DD} = 5V, V_{O} = 0.5V \text{ or } 4.5V$	3.5		3.5			3.5		
	Input Voltage	$V_{DD} = 10V, V_{O} = 1V \text{ or } 9V$	7.0		7.0			7.0		V
		$V_{DD} = 15V, V_{O} = 1.5V \text{ or } 13.5V$	11.0		11.0			11.0		
I <sub>OL</sub>	LOW Level Output	$V_{DD} = 5V, V_{O} = 0.4V$	0.64		0.51	0.88		0.36		
	Current (Note 7)	$V_{DD} = 10V, V_{O} = 0.5V$	1.6		1.3	2.25		0.9		mA
		$V_{DD} = 15V, V_{O} = 1.5V$	4.2		3.4	8.8		2.4		
I <sub>OH</sub>	HIGH Level Output	$V_{DD} = 5V, V_{O} = 4.6V$	-0.64		-0.51	-0.88		-0.36		
	Current (Note 7)	$V_{DD} = 10V, V_{O} = 9.5V$	-1.6		-1.3	-2.25		-0.9		mA
		$V_{DD} = 15V, V_{O} = 13.5V$	-4.2		-3.4	-8.8		-2.4		
I <sub>IN</sub>	Input Current	V <sub>DD</sub> = 15V, V <sub>IN</sub> = 0V		-0.1		-10 <sup>-5</sup>	-0.1		-1.0	^
		$V_{DD} = 15V, V_{IN} = 15V$		0.1		10 <sup>-5</sup>	0.1		1.0	μА

Note 6: V<sub>SS</sub> = 0V unless otherwise specified.

Note 7:  $I_{OH}$  and  $I_{OL}$  are tested one output at a time.

### AC Electrical Characteristics (Note 8)

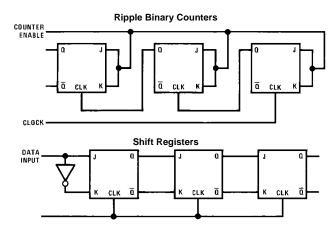
 $T_A = 25$  °C,  $C_L = 50$  pF,  $t_{rCL} = t_{fCL} = 20$  ns, unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Units
t <sub>PHL</sub> or t <sub>PLH</sub>	Propagation Delay Time	V <sub>DD</sub> = 5V		200	400	
	from Clock to Q or Q	V <sub>DD</sub> = 10V		80	160	ns
		V <sub>DD</sub> = 15V		65	130	
t <sub>PHL</sub> or t <sub>PLH</sub>	Propagation Delay Time	V <sub>DD</sub> = 5V		170	340	
	from Set to $\overline{\mathbb{Q}}$ or Reset to $\mathbb{Q}$	V <sub>DD</sub> = 10V		70	140	ns
		V <sub>DD</sub> = 15V		55	110	
t <sub>PHL</sub> or t <sub>PLH</sub>	Propagation Delay Time	V <sub>DD</sub> = 5V		110	220	
	from Set to Q or	V <sub>DD</sub> = 10V		50	100	ns
	Reset to Q	V <sub>DD</sub> = 15V		40	80	
t <sub>S</sub>	Minimum Data Setup Time	V <sub>DD</sub> = 5V		135	270	
		V <sub>DD</sub> = 10V		55	110	ns
		V <sub>DD</sub> = 15V		45	90	
t <sub>THL</sub> or t <sub>TLH</sub>	Transition Time	V <sub>DD</sub> = 5V		100	200	
		V <sub>DD</sub> = 10V		50	100	ns
		V <sub>DD</sub> = 15V		40	80	
$f_{CL}$	Maximum Clock Frequency	V <sub>DD</sub> = 5V	2.5	5		
	(Toggle Mode)	$V_{DD} = 10V$	6.2	12.5		MHz
		$V_{DD} = 15V$	7.6	15.5		
t <sub>rCL</sub> or t <sub>fCL</sub>	Maximum Clock Rise	V <sub>DD</sub> = 5V	15			
	and Fall Time	$V_{DD} = 10V$	10			μs
		$V_{DD} = 15V$	5			
t <sub>W</sub>	Minimum Clock Pulse	$V_{DD} = 5V$		100	200	
	Width $(t_{WH} = t_{WL})$	V <sub>DD</sub> = 10V		40	80	ns
		$V_{DD} = 15V$		32	65	
t <sub>WH</sub>	Minimum Set and	$V_{DD} = 5V$		80	160	
	Reset Pulse Width	$V_{DD} = 10V$		30	60	ns
		V <sub>DD</sub> = 15V		25	50	
C <sub>IN</sub>	Average Input Capacitance	Any Input		5	7.5	pF
C <sub>PD</sub>	Power Dissipation Capacity	Per Flip-Flop		35		pF
		(Note 9)		1		

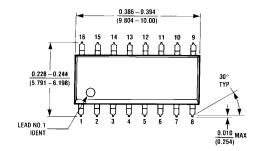
Note 8: AC Parameters are guaranteed by DC correlated testing.

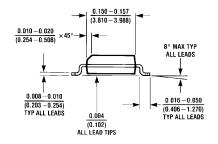
Note 9: C<sub>PD</sub> determines the no load AC power consumption of any CMOS device. For complete explanation, see 74C Family Characteristics application note, AN-90.

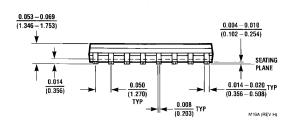
### **Typical Applications**



### Physical Dimensions inches (millimeters) unless otherwise noted

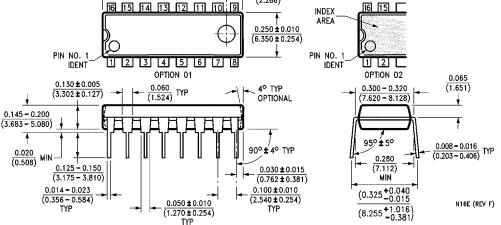






16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow Package Number M16A

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16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N16E

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